

DESCRIPTION:

With high ability to withstand the shock loading of large current, **VSA08/VSB08** triacs provide high dv/dt rate with strong resistance to electromagnetic interface. With high commutation performances, 3 quadrants products especially recommended for use on inductive load.



MAIN FEATURES

Symbol	Value	Unit
I _{T(RMS)}	8	Α
V _{DRM} /V _{RRM}	600/800/1200	V



ABSOLUTE MAXIMUM RATINGS

Parameter		Symbol	Value	Unit
Storage junction temperature range		T _{stg}	-40 - 150	$^{\circ}$
Operating junction temperature range		Tj	-40 - 125	$^{\circ}$
Repetitive peak of	f-state voltage (Tj=25℃)	V _{DRM}	600/800/1200	V
Repetitive peak reverse voltage (Tj=25℃)		V _{RRM}	600/800/1200	V
Non repetitive surge peak Off-state voltage		V _{DSM}	V _{DRM} +100	V
Non repetitive peak reverse voltage		V _{RSM}	V _{RRM} +100	V
RMS on-state current	TO-251/TO-220C TO-220B(Non-Ins) (Tc=100°C) TO-220A(Ins)/ TO-220F(Ins) (Tc=95°C) TO-262 (Tc=90°C)	I _{T(RMS)}	8	А
Non repetitive surge peak on-state current (full cycle, F=50Hz)		Ітѕм	80	Α

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I ² t value for fusing (tp=10ms)	l ² t	32	A ² s
Critical rate of rise of on-state current (I _G =2×I _{GT})	dI/dt	50	A/µs
Peak gate current	I _{GM}	4	Α
Average gate power dissipation	P _{G(AV)}	1	W
Peak gate power	Р	5	W

3 Quadrants

Symbol	Test Condition	Quadrant			Value			
				TW	SW	CW	BW	Unit
l _{GT}	- V _D =12V R _L =33Ω	I - II -III	MAX	5	10	35	50	mA
V _{GT}		I - II -III	MAX	1.5				V
V _{GD}	$V_D=V_{DRM}T_j=125$ °C R _L =3.3KΩ	I - II -III	MIN	0.2			V	
IL	I _G =1.2I _G т	I -III	MAX	20	25	50	70	m ^
		II	IVIAA	25	35	70	90	mA
Ін	I _{TM} =100mA		MAX	15	20	40	60	mA
dV/dt	V _D =2/3V _{DRM} Gate Open T _j =125℃		MIN	50	200	500	1000	V/µs

4 Quadrants

Symbol	Test Condition Quadrant	Quadrant		Va	Unit	
	rest Condition	Quadrant		С	В	Oillt
I _{GT}		I - II -III	MAX	25	50	mA
	V _D =12V R _L =33Ω	IV		50	70	
V _{GT}		ALL	MAX	1.5		V
V _{GD}	V _D =V _{DRM} T _j =125℃ R _L =3.3KΩ	ALL	MIN	0	V	
l _L	I _G =1.2I _{GT}	I -III-IV	MAX	50	70	mA
		II		70	90	
lн	I _{TM} =200mA		MAX	40	60	mA
dV/dt	V _D =2/3V _{DRM} Gate Open T _j =125℃		MIN	200	500	V/µs



Symbol	Parameter		Value(MAX)	Unit
V _{TM}	I _{тм} =11A tp=380µs	Tj=25℃	1.5	V
IDRM	\/\/\/- =\/	Tj=25℃	5	μΑ
I _{RRM}	V _D =V _{DRM} V _R =V _{RRM}	Tj=125℃	1	mA

THERMAL RESISTANCES

Symbol	Parame	eter	Value	Unit
	junction to case(AC)	TO-251	2.1	°C/W
R _{th(j-c)}		TO-220A(Ins)	2.7	
		TO-220C/ TO-220B(Non-Ins)	1.8	
		TO-220F(Ins)	2.9	
		TO-262	3.0	



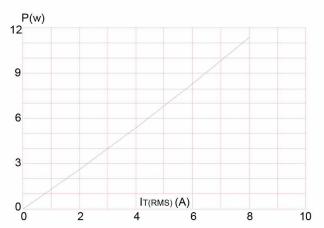


FIG.3: Surge peak on-state current versus number of cycles

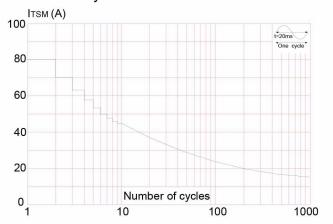
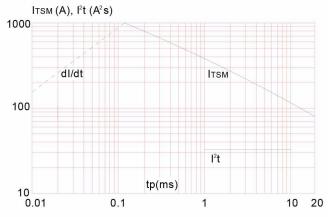


FIG.5: Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp<20ms, and corresponging value of I²t (dI/dt < 50A/µs)



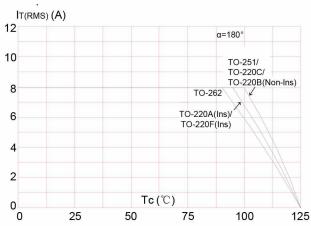


FIG.4: On-state characteristics (maximum values)

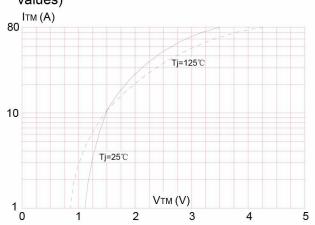


FIG.6: Relative variations of gate trigger current, holding current and latching current versus junction temperature

